



08/06/03 4641-59261 206139

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Ushio *et al.*

Application No. 09/881,445

Filed: June 13, 2001

For: LAYER-THICKNESS DETECTION  
METHODS AND APPARATUS FOR WAFERS  
AND THE LIKE, AND POLISHING  
APPARATUS

Examiner: Not yet assigned

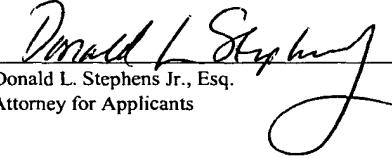
Date: August 6, 2003

Art Unit: 2818

Confirmation No. 7027

**CERTIFICATE OF MAILING**

I hereby certify that this paper and the documents referred to as being attached or enclosed herewith are being deposited with the United States Postal Service on August 6, 2003 as First Class Mail in an envelope addressed to: COMMISSIONER FOR PATENTS, P.O. BOX 1450, ALEXANDRIA, VA 22313-1450.

  
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Attorney for Applicants

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**  
**PURSUANT TO 37 C.F.R. § 1.97(b)**

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Listed on the accompanying form PTO-1449 and enclosed herewith are several English-language and non-English-language documents. English translations of at least part of the respective texts have been provided for most of the non-English-language documents, except where the non-English-language document corresponds to an U.S. patent cited herein and provided herewith (as indicated on accompanying form PTO-1449). One non-English document (JP56-153207) has an English abstract, as noted on the form PTO-1449.

Applicants respectfully request that these documents be listed as references cited on the issued patent.

Applicants filed this Information Disclosure Statement ("IDS") within three months of the filing date of a national application, within three months of the date of entry of the national stage as set forth in § 1.491 in an international application, before the mailing date of a first Office action on the merits, or before the mailing of a first Office action after the filing of request for continued examination under § 1.114. As a result, no fee should be required to file this IDS. However, if the Patent Office determines that a fee is required for Applicants to file this IDS, please see the attached Transmittal Letter for Deposit Account authority.

The filing of this IDS shall not be construed to be an admission by Applicants or the undersigned that the information cited in this statement is, or is considered to be, prior art or otherwise material to patentability as defined in Rule 56.

Respectfully submitted,

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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> 		<b>Attorney Docket Number</b>	4641-59261
		<b>Application Number</b>	09/881,445
		<b>Filing Date</b>	June 13, 2001
		<b>First Named Inventor</b>	Ushio
		<b>Art Unit</b>	2818
		<b>Examiner Name</b>	Not yet assigned
<b>U.S. PATENT DOCUMENTS</b>			
<b>Examiner's Initials*</b>	<b>Cite No. (optional)</b>	<b>Number</b>	<b>Date</b>
		4,645,349	Feb. 24, 1987
		4,744,660	May 17, 1988
		5,696, 583	Dec. 9, 1997
		5,893,796	Apr. 13, 1999
		5,964,643	Oct. 12, 1999
		6,045,439	Apr. 4, 2000
		6,280,290 B1	Aug. 28, 2001
		US2001/0036805 A1	Nov. 1, 2001
		6,537,133 B1	Mar. 25, 2003
<b>FOREIGN PATENT DOCUMENTS</b>			
<b>Examiner's Initials*</b>	<b>Cite No. (optional)</b>	<b>Number</b>	<b>Date</b>
		56-153207 /	Nov. 27, 1981
		60-305 /	Jan. 5, 1985
		61-76904 /	April 19, 1986
		61-235708 /	Oct. 21, 1986
		63-50703 /	March 3, 1988
		64-57107 /	March 3, 1989
		6-147838 /	May 27, 1994

<b>EXAMINER SIGNATURE:</b>	<b>DATE CONSIDERED:</b>
* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.	

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>		<b>Attorney Docket Number</b>	4641-59261
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		<b>First Named Inventor</b>	Ushio
		<b>Art Unit</b>	2818
		<b>Examiner Name</b>	Not yet assigned
	6-252113	Sept. 9, 1994	Japan (w/English translation)
	8-145631	June 7, 1996	Japan (corresponds to US 5,696,583)
	9-7985	Jan. 10, 1997	Japan (corresponds to US 6,537,133)
	EP 0824995 A1	Feb. 25, 1998	EPC
	EP 0738561 B1	Jan. 23, 2002	EPC
<b>Examiner's Initials*</b>	<b>Cite No. (optional)</b>	<b>OTHER DOCUMENTS</b>	
		Ushio <i>et al.</i> , "In-situ monitoring of CMP process utilizing 0-order spectrometry," <i>CMP-IMC Conference</i> , pp. 23-29, Feb. 11-12, 1999	
		Ushio <i>et al.</i> , "In-situ monitoring of CMP process utilizing 0-order spectrometry," <i>IMIC Journal on CMP</i> , Vol. 1, No. 1, Fall, 1999	

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